

Notice of References Cited	Application/Control No. 10/584,702		Applicant(s)/Patent Under Reexamination ALVARADO ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,621,912 A	04-1997	Borruso et al.	718/1
*	B	US-6,157,721 A	12-2000	Shear et al.	380/255
*	C	US-6,279,091 B1	08-2001	Kikuchi et al.	711/170
*	D	US-2002/0023214 A1	02-2002	Shear et al.	713/170
*	E	US-2002/0069263 A1	06-2002	Sears et al.	709/218
*	F	US-6,496,847 B1	12-2002	Bugnion et al.	718/1
*	G	US-2003/0121003 A1	06-2003	Soshalsky et al.	715/513
*	H	US-2003/0135748 A1	07-2003	Yamada et al.	713/193
*	I	US-2003/0182626 A1	09-2003	Davidov et al.	715/513
*	J	US-2003/0181193 A1	09-2003	Wilhelmsson et al.	455/403
*	K	US-2003/0208748 A1	11-2003	Levin et al.	717/134
*	L	US-2003/0232618 A1	12-2003	Le et al.	455/412.2
*	M	US-2003/0233465 A1	12-2003	Le et al.	709/231

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	P					
	Q					
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	S					
	I					

NON-PATENT DOCUMENTS

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	U	
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	X	

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0229557 A1	12-2003	RICHMANN et al.	705/36
*	B	US-2003/0224769 A1	12-2003	Solve et al.	455/418
*	C	US-2004/0039741 A1	02-2004	Benson et al.	707/9
*	D	US-2004/0034853 A1	02-2004	Gibbons et al.	717/174
*	E	US-2004/0142682 A1	07-2004	Kamiya et al.	455/418
*	F	US-2004/0153774 A1	08-2004	Gavish et al.	714/025
*	G	US-2004/0157593 A1	08-2004	Lee et al.	455/418
*	H	US-2004/0158577 A1	08-2004	Chu et al.	707/103.00R
*	I	US-2004/0158813 A1	08-2004	Xia et al.	717/116
*	J	US-2004/0267804 A1	12-2004	Fresko et al.	707/102
*	K	US-2005/0003810 A1	01-2005	Chu et al.	455/418
*	L	US-2005/0034110 A1	02-2005	Lee et al.	717/141
*	M	US-2005/0138192 A1	06-2005	Encarnacion et al.	709/230

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0132363 A1	06-2005	Tewari et al.	718/001
*	B	US-6,922,835 B1	07-2005	Susser et al.	719/316
*	C	US-6,944,699 B1	09-2005	Bugnion et al.	710/269
*	D	US-2005/0235291 A1	10-2005	Kamiya et al.	719/315
*	E	US-2006/0070044 A1	03-2006	Romanovski et al.	717/136
*	F	US-2006/0112268 A1	05-2006	Kamiya et al.	713/165
*	G	US-7,039,033 B2	05-2006	Haller et al.	370/338
*	H	US-2006/0129628 A1	06-2006	Kamiya et al.	709/203
*	I	US-7,069,275 B2	06-2006	Salmen, Helmut	1/1
*	J	US-2006/0156296 A1	07-2006	Goldberg, Athomas Martin	717/168
*	K	US-7,200,848 B1	04-2007	Slaughter et al.	719/317
*	L	US-2007/0143444 A1	06-2007	Kamiya et al.	709/219
*	M	US-7,260,618 B2	08-2007	Ahonen, Petri	709/219

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,334,076 B2	02-2008	Hendel et al.	711/6
*	B	US-7,337,436 B2	02-2008	Chu et al.	717/140
*	C	US-7,350,194 B1	03-2008	Alpern, David M.	717/124
*	D	US-7,415,270 B2	08-2008	Wilhelmsson et al.	455/419
*	E	US-7,426,721 B1	09-2008	Saulpaugh et al.	717/144
*	F	US-7,536,181 B2	05-2009	Solve et al.	455/419
*	G	US-7,584,471 B2	09-2009	Bjare et al.	717/178
*	H	US-7,640,542 B2	12-2009	Herenyi et al.	717/177
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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	W	
	X	

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Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.